Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/516,912	HORIUCHI ET AL.	
Examiner	Art Unit	

Patrick Hamo

3746

	SEARCHED			
Class	Subclass	Date	Examiner	
417	42	12/12/2006	PH	
417	44.1	12/12/2006	PH	
417	44.2	12/12/2006	PH ·	
417	287	12/12/2006	PH	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
417/42, 44.1, 44.2, and 287 recommended by M Kozco	12/12/2006	РН
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